

FDP6670AL/FDB6670AL

N-Channel Logic Level PowerTrench^o MOSFET

General Description

This N-Channel Logic Level MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

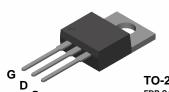
These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable $R_{\text{DS(ON)}}$ specifications.

The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

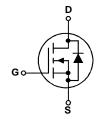
It has been optimized for low gate charge, low $R_{\mbox{\scriptsize DS(ON)}}$ and fast switching speed.

Features

- 80 A, 30 V $R_{DS(ON)} = 6.5 \text{ m}\Omega$ @ $V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 8.5 \text{ m}\Omega$ @ $V_{GS} = 4.5 \text{ V}$
- Critical DC electrical parameters specified at elevated temperature
- High performance trench technology for extremely low $R_{\mbox{\scriptsize DS}(\mbox{\scriptsize ON})}$
- 175°C maximum junction temperature rating







TO-220 S TO-263AB FDP Series FDB Series

Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		30	V
V _{GSS}	Gate-Source Voltage		± 20	V
I _D	Drain Current - Continuous	(Note 1)	80	А
	- Pulsed	(Note 1)	240	
P _D	Total Power Dissipation @ T _C = 25°C		68	W
	Derate above 25°C		0.45	W/°C
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-65 to +175	°C

Thermal Characteristics

R _{θJC}	Thermal Resistance, Junction-to-Case	2.2	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDB6670AL	FDB6670AL	13"	24mm	800 units
FDP6670AL	FDP6670AL	Tube	n/a	45

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	ource Avalanche Ratings (Note	1)	1	l		
W _{DSS}	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = 15 \text{ V}, \qquad I_{D} = 80 \text{ A}$			114	mJ
I _{AR}	Maximum Drain-Source Avalanche Current				80	Α
Off Char	acteristics		•			
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_D = 250 \mu\text{A}$	30			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		24		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			1	μΑ
I _{GSS}	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			± 100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_{D} = 250 \mu A$	1	1.9	3	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to 25°C		- 5		mV/°C
R _{DS(on)}	Static Drain–Source On– Resistance	$\begin{aligned} &V_{GS} = 10 \text{ V}, &I_{D} = 40 \text{ A} \\ &V_{GS} = 4.5 \text{ V}, &I_{D} = 37 \text{ A} \\ &V_{GS} = 10 \text{ V}, I_{D} = 40 \text{ A}, T_{J} = 125^{\circ}\text{C} \end{aligned}$		5.2 6.5 7.2	6.5 8.5 9.7	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 10 \text{ V}$	80			Α
g _{FS}	Forward Transconductance	$V_{DS} = 10V$, $I_{D} = 40 \text{ A}$		115		S
Dynamic	Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$		2440		pF
Coss	Output Capacitance	f = 1.0 MHz		580		pF
C _{rss}	Reverse Transfer Capacitance			250		pF
R _G	Gate Resistance	V _{GS} = 15 mV, f = 1.0 MHz		1.4		Ω
Switchin	g Characteristics (Note 2)		•	,		
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 10V, I_{D} = 1 A,$		13	23	ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		13	23	ns
t _{d(off)}	Turn-Off Delay Time	1		42	68	ns
t _f	Turn-Off Fall Time			15	27	ns
Q _g	Total Gate Charge	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 40 \text{ A},$		24	33	nC
Q_{gs}	Gate-Source Charge	$V_{GS} = 5 \text{ V}$		7		nC
Q_{gd}	Gate-Drain Charge			9		nC
Drain-Se	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain–Source	_			80	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 40 \text{ A}$ (Note 1)		0.9	1.3	V
t _{rr}	Diode Reverse Recovery Time	I _F = 40 A,		34		nS
Q _{rr}	Diode Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$	-	24		nC

Notes

^{1.} Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0%

Typical Characteristics

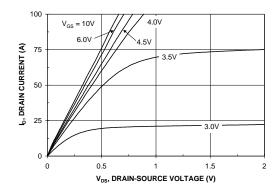


Figure 1. On-Region Characteristics.

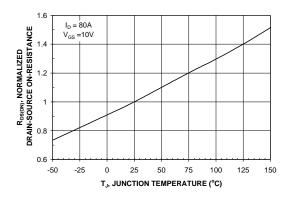


Figure 3. On-Resistance Variation with Temperature.

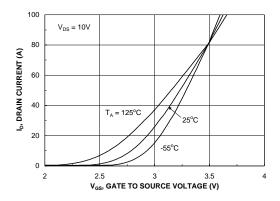


Figure 5. Transfer Characteristics.

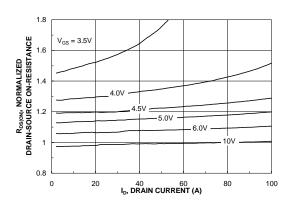


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

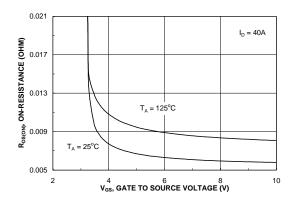


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

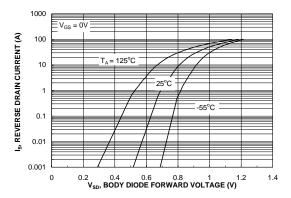
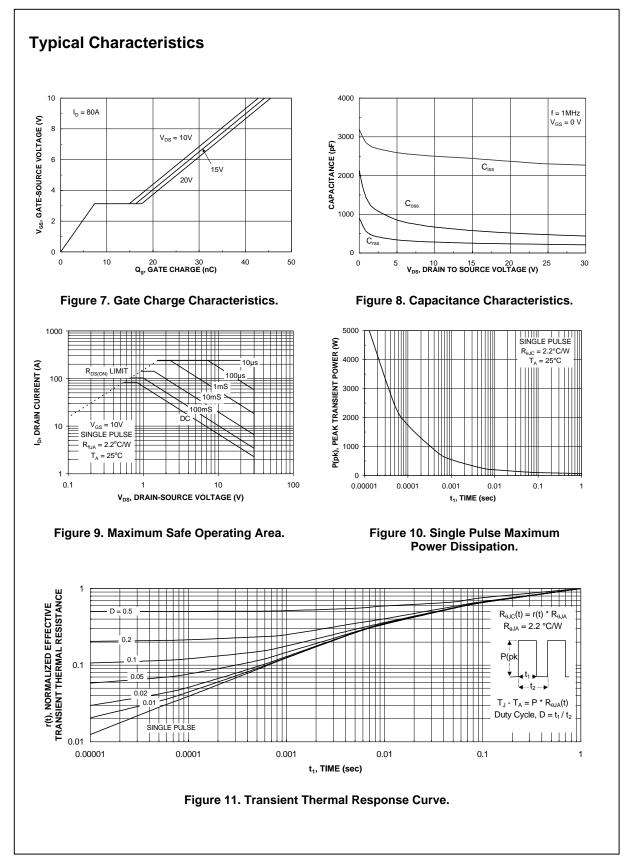


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.



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PRODUCT STATUS DEFINITIONS

Definition of Terms

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No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.		
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